

AMENDMENTS TO THE CLAIMS

The following listing of claims will replace all prior versions, and listings of claims in the application:

Listing Of Claims:

1. (Currently Amended) A method for testing pre-designated configuration space settings in a chip ~~configuration settings~~, comprising the steps of:

providing a main board including a chip to be tested, the chip having a pre-designated configuration space defined therein;

providing a BIOS program including a configuration space setting ~~chip test process~~ therein;

starting power for said main board;

performing a power -on self-test;

loading said BIOS program; and

executing said configuration space setting test process to testing said configuration space for the pre-designated configuration space settings in a ~~configuration space of said chip~~.

2. (Currently Amended) The method according to Claim 1, wherein said configuration test process included in said BIOS program ~~comprising~~ comprises the steps of:

providing a test datum;

providing an expected result datum corresponding to said test datum;
inputting said test datum into said BIOS;
enabling a register corresponding to said chip configuration space
depending on said test datum;
triggering said chip to perform the corresponding operation;
obtaining a result datum that is produced after operation ~~operating~~ of
said chip; and
comparing said obtained result datum with said expected result
datum.

3. (Currently Amended) The method according to Claim 2, further comprising
the [[a]] step of recording said comparison result.

4. (Currently Amended) The method according to Claim 3, further comprising
the [[a]] step of generating a difference report.

5. (Currently Amended) The method according to Claim 1, wherein said
configuration test process included in said BIOS program comprises ~~comprising~~
the steps of:

providing at least one set[[s]] of test data;

providing at least one set[[s]] of expected result data corresponding to said test data;

inputting said test data;

enabling a register corresponding to said chip configuration space depending on said test data;

obtaining corresponding result data after operating of said chip in accordance with said test data; and

comparing said obtained result data with said corresponding expected result data.

6. (Currently Amended) The method according to Claim 5, wherein said test data ~~are~~ is implemented in the form of a data table list.

7. (Currently Amended) The method according to Claim 5, wherein said expected result data ~~are~~ is implemented in the form of a data table list.

8. (Currently Amended) The method according to Claim 5, further comprising [[a]] the step of recording said comparison results

9. (Currently Amended) The method according to Claim 8, wherein said records of said comparison results are implemented in the form of a data table list.

10. (Currently Amended) The method according to Claim 9, wherein each of said records of said comparison results includes a result and difference obtained from said comparison.

11. (Currently Amended) The method according to Claim 5, further comprising ~~[[a]]~~ the step of generating a test report.

12. (Currently Amended) The method according to Claim 10, further comprising the ~~[[a]]~~ step of generating a difference report.